
DDR3 DIMM Low Contact Resistance Solder tail Sockets

1. SCOPE

1.1. Content

This specification covers performance, tests and quality requirements for the Tyco Electronics DDR3 Dual In-line Memory Module (DIMM) Low Contact Resistance Solder tail Connector used primarily in desktop and server applications where soldering is acceptable.

1.2. Qualification

When tests are performed on the subject product line, procedures specified in Figure 1 shall be used. All inspections shall be performed using the applicable inspection plan and product drawing.

1.3. Qualification Test Results

Qualification testing on the subject product line was completed. The Qualification Test Report number for this test is 501-115000.

2. APPLICABLE DOCUMENTS

The following documents form a part of this specification to the extent specified herein. Unless otherwise specified, the latest edition of the document applies. In the event of conflict between the requirements of this specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of this specification and the referenced documents, this specification shall take precedence.

2.1. Tyco Electronics Documents

- 109 series: Test Specification as indicated in Figure 1
- 109-197: Test Specification (AMP Test Specifications vs EIA and IEC Test Methods)
- 114-13154: Application Specification
- 501-11500: Qualification Test Report

2.2. Industry Standards

EIA-364: Electrical Connector/Socket Test Procedures Including Environmental Classifications

3. REQUIREMENTS

3.1. Design and Construction

Product shall be of the design, construction and physical dimensions specified on the applicable product drawing.

3.2. Materials

Materials used in the construction of this product shall be as specified on the applicable product drawing.

3.3. Ratings

- Voltage: 25 Volts AC
- Current: 0.5 Ampere
- Temperature: -55°C to 105°C

3.4. Performance and Test Description

Product is designed to meet the electrical, mechanical and environmental performance requirements specified in Figure 1. Unless otherwise specified, all tests shall be performed at ambient environmental conditions.

3.5. Test Requirements and Procedures Summary

Test Description	Requirement	Procedure
Initial examination of product.	Meets requirements of product drawing.	EIA-364-18. Visual and dimensional (C of C) inspection per product drawing.
Final examination of product.	Meets visual requirements.	EIA-364-18. Visual inspection.
ELECTRICAL		
Low level contact resistance.	10 milliohms maximum initial. ΔR 10 milliohms maximum.	EIA-364-23. Subject specimens mated with bussed module boards to 100 milliamperes maximum and 20 millivolts maximum open circuit voltage. Measure all 240 positions. See Figure 3.
Insulation resistance.	1000 megohms minimum.	EIA-364-21. 500 volts DC, 2 minute hold. Test between adjacent contacts of mounted specimens.
Withstanding voltage.	One minute hold with no breakdown or flashover.	EIA-364-20, Condition I. 500 volts AC at sea level. Test between adjacent contacts of unmated and mounted specimens.
Current carrying capacity.	30°C maximum temperature rise at specified current.	EIA 364-70. Connect 6 consecutive contacts on 1 side of specimen in series and load with 0.5 ampere. Place a thermocouple through a small hole in the housing as close to the contact as possible.

Figure 1 (continued)

Test Description	Requirement	Procedure
MECHANICAL		
Reseating.	See Note.	Manually unplug and plug module card 3 times with latches enabled.
Solderability, lead free	95% coverage. No physical damage; contact gap within manufacturer's tolerance.	EIA-364-52, Class 1, Category 3 Thirty seconds exposure at 190°C oven. Processing criteria: solder 260 ± 5°C for 5 seconds.
Vibration, random.	See Note.	EIA-364-28. Module weight 35 ± 5 g with the center of gravity 20~25 mm [.9 in] from the module mating edge. Duration: 10 minutes per axis for all 3 axes on all samples. Frequency range: 5 to 500 Hz. 5 to 20 Hz (slope): (0.01 g ² /Hz) at 5 Hz; (0.02 g ² /Hz) at 20 Hz; 20 to 500 Hz (flat): (0.02 g ² /Hz) at 20 Hz. Input acceleration is 3.13 g RMS; Random control limit tolerance: ± 3 dB. See Figure 4.
Mechanical shock.	See Note.	EIA-364-27. Module weight 35 ± 5 g with the center of gravity 20~25 mm [0.9 in] from the module mating edge. Profile: Trapezoidal shock of 50 g ± 10%. Duration: 11 ms. Minimum velocity change: 67 cm/sec ± 10%. Quantity: Three drops in each of 6 directions. See Figure 4.
Durability.	Rating of 25 cycles as determined by EIA-TS-364-1000.1 See Note.	EIA-364-9. Mate and unmate specimens for 25 cycles at a maximum rate of 500 cycles per hour. Use the same board for the 1 st and 25 th cycles and subsequent tests. Use a separate board for the 2 nd through the 24 th cycles.

Figure 1 (continued)

Test Description	Requirement	Procedure
Mating force	<106.75 N [24 lbf].	EIA-364-5. Measure force necessary to mate specimens with a 1.37 mm [.054 in] steel gage at a maximum rate of 5 mm [.2 in] per minute See Figure 5.
Wrong card insertion.	> 222.4 N [50 lbf].	EIA-364-5. Measure force necessary to mate specimens with a DDR2 module card with a FB-DIMM key location.
Latch opening force.	32.4 N [7.3 lbf] maximum per latch. See Note.	EIA-364-13. Measure force necessary to unmate specimens from a 1.37 mm [.054 in] steel gage at a maximum rate of 5 mm [.2 in] per minute. See Figure 5.
Unmating force per pin pair.	0.14 N [14 gf] minimum.	EIA-364-13. With both latches removed, measure force necessary to unmate specimens from a nominal (1.27 mm [.05 in] thick module card at a maximum rate of 5 mm [.2 in] per minute. See Figure 5.
Contact retention.	3 N [300 lbf] minimum per pin. No movement of contact more than 0.38 mm [.015 in].	EIA-364-29. Apply specified load to contact tail and hold for 6 seconds.
Fork lock retention (where applicable).	13.3 N [3lbf] minimum per fork lock. Maximum movement of 0.38 mm [.015]	EIA-364-29 Apply specified load to fork lock and hold for 6 seconds.
Connector insertion force into PCB	<33.21 N [7.47 lbf] per fork lock.	Press socket onto board at a rate of 5 mm [.2 in] per minute. Measure force at nominal fork lock hole diameter 2.45 mm [.097 in].
Maximum force on connector.	Less than 0.076 mm [0.003 in] movement.	Apply 68.1 kg [150 lb] load to the top of a 1.37 mm [.054 in] steel gage after the gage has been fully seated and is bottomed out. Maintain force for 30 seconds. See Figure 5.
Contact backout wipe.	No discontinuities of 1 microsecond or longer duration	Fully seat daisy chain module. Pull module upward until stopped by latches while monitoring for discontinuities.

Figure 1 (continued)

Test Description	Requirement	Procedure
ENVIRONMENTAL		
Solvent resistance.	See Note.	EIA 364-11, Solvent Group 1.
Thermal shock.	See Note.	EIA-364-32, Test Condition I. Subject mated and mounted specimens to 10 cycles between -55 and 85°C. Thirty minute dwell at temperature extremes.
Humidity-temperature cycling.	See Note.	EIA-364-31, Method III. Subject mated and mounted specimens to 24 cycles between 25 ± 3 °C at 80% ± 3% RH and 65 ± 3°C at 50% ± 3% RH. Ramp times shall be 0.5 hour with 1 hour dwell time.
Temperature cycling (gold flash plating)	See Note.	Subject mated and mounted specimens to 500 cycles between 15 ± 3°C and 85 ± 3°C as measured on the specimen. Ramps times shall be a minimum of 2°C per minute. Dwell times shall ensure that the contacts reach the temperature extreme (5 minutes minimum). Humidity not controlled.
Temperature life	See Note	EIA-364-17, Method A, Test Condition 4. Subject mated and mounted specimens to 105°C for 726 hours.
Mixed flowing gas (15 and 30 microinch minimum gold plating)	See Note.	EIA-364-65, Class IIA (4 gas). Three specimens unmated for 5 days, mated for 5 days. Three specimens mated for 10 days. Store module cards at laboratory ambient during the unmated portion of the exposure.
Industrial gas SO ₂ (gold flash plating)	See Note.	EIA-364-65A SO ₂ Gas: 10ppm, 95%RH 25°C, 24 hours
Thermal disturbance.	See note.	Subject mated and mounted specimens to 10 cycles between 15 ± 3°C and 85 ± 3°C as measured on the part. Ramps shall be a minimum of 2°C per minute. Dwell times shall ensure that the contacts reach the temperature extreme (5 minutes minimum). Humidity not controlled.

NOTE

Shall meet visual requirements, show no physical damage, and meet requirements of additional tests as specified in the Product Qualification and Requalification Test Sequence shown in Figure 2.

Figure 1 (end)

3.6. Product Qualification and Requalification Test Sequence

Test or Examination	Test Group (a)												
	1	2	3	4(h)	5	6	7	8	9	10	11	12(k)	13(k)
	Test Sequence (b)												
Initial examination of product	1	1	1	1	1	1	1	1	1	1	1	1	1
Low level contact resistance	2,6,8	2,7,9,13	2,4,6,8,10	2,5,7,9,11								2,5,7,9	2,5,7,9,11
Insulation resistance		3,10											
Withstanding voltage		4,11											
Current carrying capacity									2				
Reseating	7	12		10								8	10
Solderability						2(c)							
Vibration, random			7										
Mechanical shock			9										
Durability	4(d)	5(d)	3	3(d)								3(d)	3(d)
Mating force					2								
Wrong card insertion								2					
Latch opening force					3								
Unmating force per pin pair										3			
Contact retention							3						
Fork lock retention							2						
Connector insertion force into PCB										2			
Maximum force on connector					4								
Contact backout wipe	3												
Solvent resistance											2		
Thermal shock		6											
Humidity-temperature cycling		8											
Thermal cycling												6	
Temperature life (c)	5		5(e)	4(e)								4(e)	4(e)
Mixed flowing gas				6(f)									
Industrial gas SO ₂													6
Thermal disturbance				8									8
Final examination of product	9	14	11	12	5	3(g)	4	3	3	4	3	10	12

NOTE

- (a) See paragraph 4.1.A.
- (b) Numbers indicate sequence in which tests are performed.
- (c) Intel 7 years lifetime test
- (d) Durability preconditioning with only 5 cycles required same card, all cycles.
- (e) Temperature life preconditioning, 385 hours duration.
- (f) Three specimens unmated for 5 days, mated for 5 days. Three specimens mated for 10 days.
- (g) Measure contact gaps across mating interface.
- (h) For 15 and 30 microinch min. gold plating part
- (k) For gold flash plating part

Figure 2

4. QUALITY ASSURANCE PROVISIONS

4.1. Qualification Testing

A. Specimen Selection

Specimens shall be prepared in accordance with applicable Instruction Sheets and shall be selected at random from current production. Test groups 1, 2, 3, 5, 8, 9, 10, 12, and 13 shall each consist of 5 specimens. Test group 4 shall each consist of 6 specimens. Test group 6 shall each consist of 10 specimens. Test group 7 and 11 shall each consist of 4 specimens.

B. Test Sequence

Qualification inspection shall be verified by testing specimens as specified in Figure 2.

4.2. Requalification Testing

If changes significantly affecting form, fit or function are made to the product or manufacturing process, product assurance shall coordinate requalification testing, consisting of all or part of the original testing sequence as determined by development/product, quality and reliability engineering.

4.3. Acceptance

Acceptance is based on verification that the product meets the requirements of Figure 1. Failures attributed to equipment, test setup or operator deficiencies shall not disqualify the product. If product failure occurs, corrective action shall be taken and specimens resubmitted for qualification. Testing to confirm corrective action is required before resubmittal.

4.4. Quality Conformance Inspection

The applicable quality inspection plan shall specify the sampling acceptable quality level to be used. Dimensional and functional requirements shall be in accordance with the applicable product drawing and this specification.

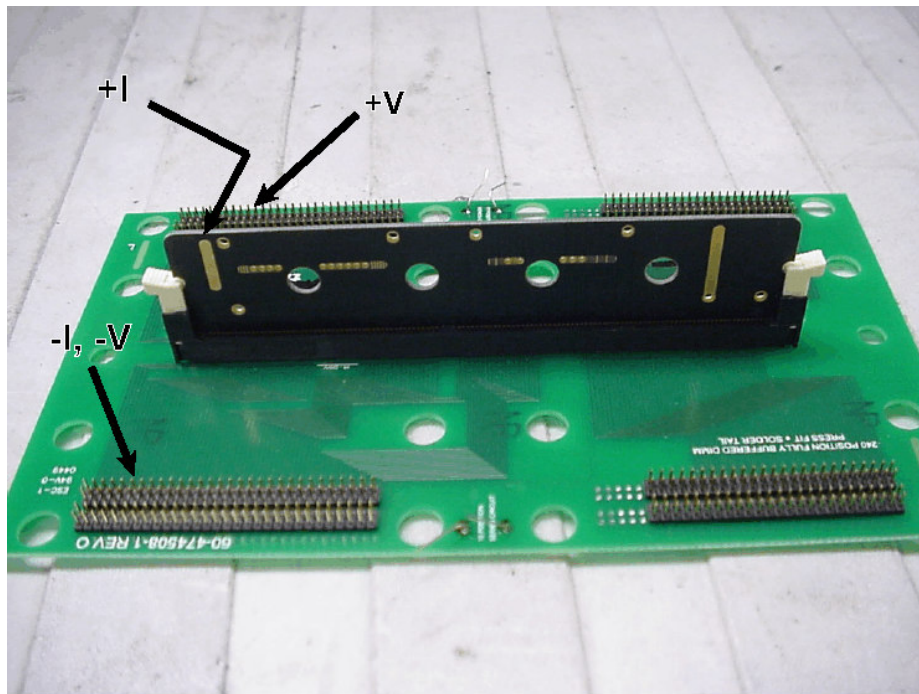


Figure 3

Low Level Contact Resistance

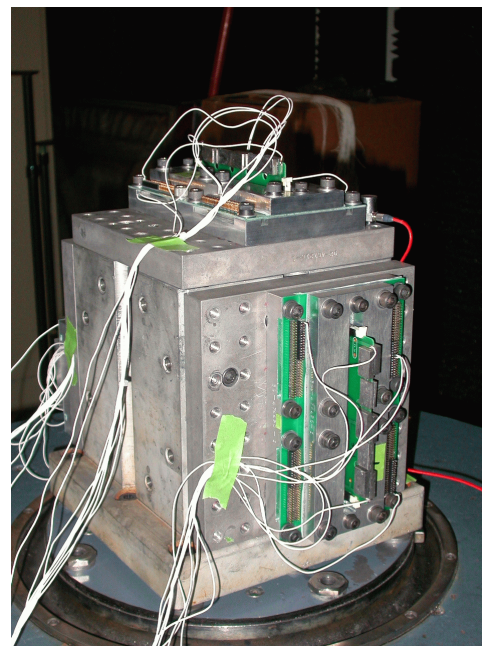
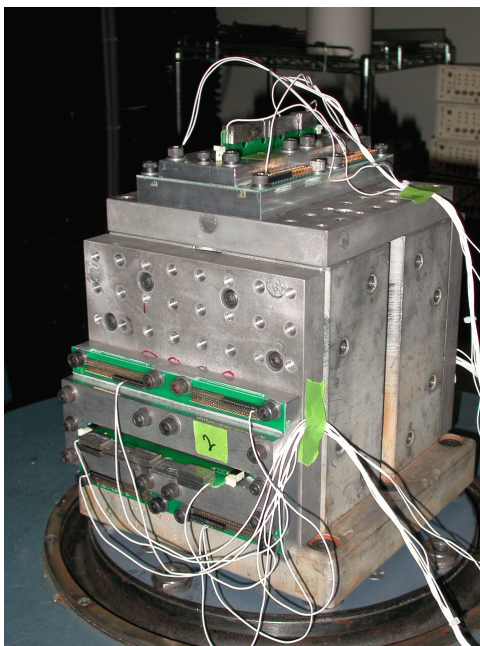
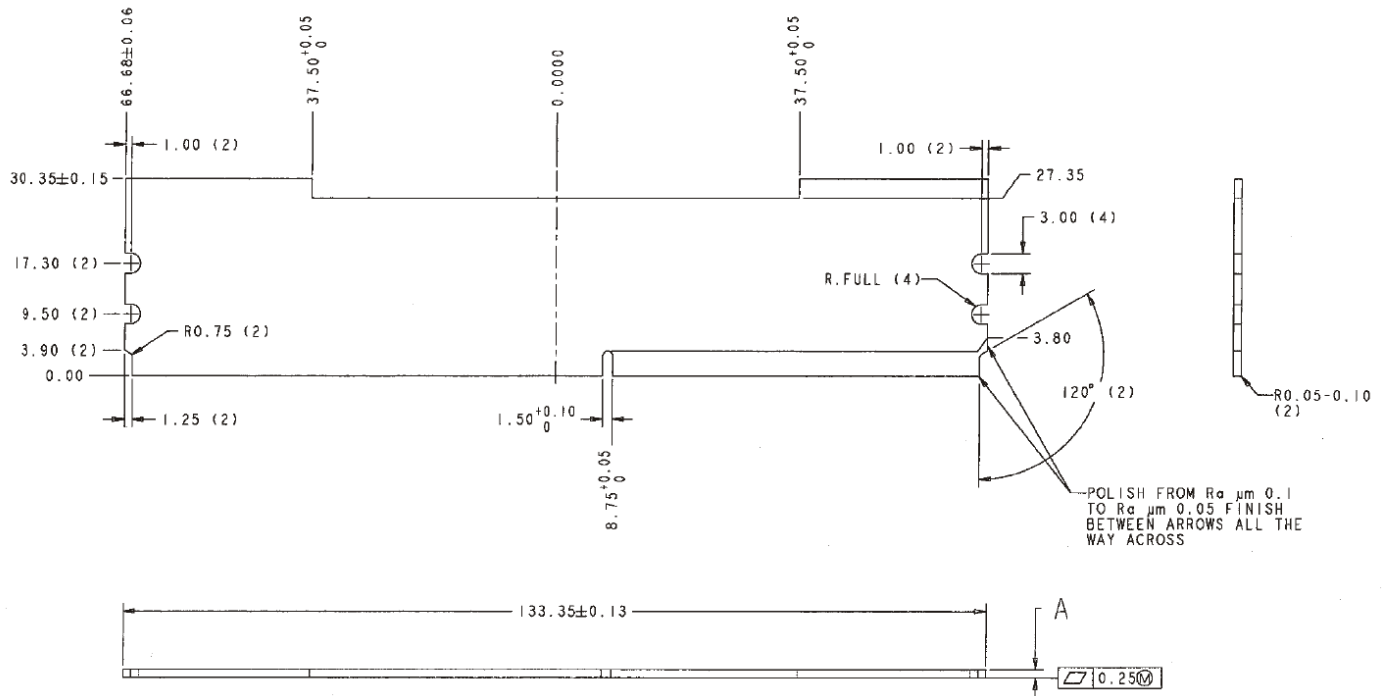


Figure 4

Vibration and Mechanical Shock



1. Material 100-99 AISI A2.
2. Heat treat 111-99 Rc 60-62

Tyco Drawing	Description	"A" Dimension
39-152462-100-3	Maximum Card	1.37 +0.013/-0.000 mm
39-152462-100-4	Normal Card	1.27 +0.013/-0.000 mm

Figure 5

DDR3 DIMM Low Contact Resistance Steel Insertion Gages